

#### **Product Change Notification / KSRA-27VTNQ916**

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16-Jul-2020

#### **Product Category:**

32-bit Microcontrollers

#### **PCN Type:**

Manufacturing Change

#### **Notification Subject:**

CCB 3658.001 Final Notice: Qualification of MPHL as an additional final test site for selected ATSAMD20G1xx and ATSAMD21G1xx Atmel device families available in 48L VQFN (7x7x0.9 mm) package.

#### **Affected CPNs:**

KSRA-27VTNQ916\_Affected\_CPN\_07162020.pdf KSRA-27VTNQ916\_Affected\_CPN\_07162020.csv

#### **Notification Text:**

PCN Status: Final notification

PCN Type: Manufacturing Change

Microchip Parts Affected:Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

**Description of Change:** Qualification of MPHL as an additional final test site for selected ATSAMD20G1xx and ATSAMD21G1xx Atmel device families available in 48L VQFN (7x7x0.9 mm) package.

#### Pre Change:

Tested at ASE9 final test site

#### Post Change:

Tested at ASE9 final test site or tested at MPHL final test site

	Pre Change	Post Change						
Final Test Site	ASE Test	ASE Test	Microchip Technology Operations (Philippines) Corporation					
	(ASE9)	(ASE9)	(MPHL)					
Base Quantity Multiple (BQM)	4000	4000						
Tape and reel	4000 units per reel	4000 units per reel	4000 units per reel					
Pin 1 Orientation for reel	Quadrant 1	Quadrant 1	Quadrant 1					
Carrier Tape Dimension (Reel)	Minor dimensional changes (see pre and post change comparison)							
Reel	Minor dimensional and color changes (see attached)							
Packing Method	Minor dimensiona	Minor dimensional changes (see pre and post change comparison)						

Impacts to Data Sheet: None

Change Impact:None

**Reason for Change:**To improve on-time delivery performance by qualifying MPHL as an additional final test site.

**Change Implementation Status:**In Progress

Estimated First Ship Date: August 16, 2020 (date code: 2034)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

#### Time Table Summary:

	May 2020				Ju			ıly 2020		August 2020						
Workweek	18	19	20	21	22	<b>→</b>	27	28	29	30	31	32	33	34	35	36
Initial PCN Issue Date					Χ											
Qual Report Availability									Χ							
Final PCN Issue Date									Χ							
Estimated Implementation Date														Х		

Method to Identify Change: Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN\_#\_Qual\_Report

Revision History:May 28, 2020: Issued initial notification

**July 16, 2020:** Issued final notification. Attached the Qualification Report. Revised the affected parts list. Provided estimated first ship date to be on August 16, 2020.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

#### **Attachments:**

PCN\_KSRA-27VTNQ916\_Pre and Post Change Summary.pdf PCN\_KSRA-27VTNQ916\_Qual\_Report.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

#### **Terms and Conditions:**

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

KSRA-27VTNQ916 - CCB 3658.001 Final Notice: Qualification of MPHL as an additional final test site for selected ATSAMD20G1xx and ATSAMD21G1xx Atmel device families available in 48L VQFN (7x7x0.9 mm) package.

#### Affected Catalog Part Numbers (CPN)

ATSAMD21G17A-MF

ATSAMD21G18A-MF

ATSAMD21G18A-MU

ATSAMD21G17A-MU

ATSAMD21G17A-MUA1

ATSAMD21G18A-MUA1

ATSAMD21G18A-MU-SLL

ATSAMD21G17A-MUT

ATSAMD21G18A-MUT

ATSAMD21G17A-MUTA1

ATSAMD21G18A-MUTA1

ATSAMD21G18A-MUTN01

ATSAMD21G17A-MFT

ATSAMD21G18A-MFT

ATSAMD20G14A-MU

ATSAMD20G15A-MU

ATSAMD20G16A-MU

ATSAMD20G17A-MU

ATSAMD20G18A-MU

ATSAMD20G17A-MU

ATSAMD20G18A-MU

ATSAMD20G16A-MU

ATSAMD20G15A-MU

ATSAMD20G14A-MU

ATSAMD20G18A-MUA2

ATSAMD20G14A-MUA2

ATSAMD20G18A-MUA2

ATSAMD20G14A-MUA2

ATSAMD20G15A-MUA2

ATSAMD20G16A-MUA2

ATSAMD20G17A-MUA2

ATSAMD20G14A-MN ATSAMD20G15A-MN

ATSAMD20G16A-MN

ATSAMD20G17A-MN

ATSAMD20G18A-MN

ATSAMD20G14A-MNT

ATSAMD20G15A-MNT

ATSAMD20G16A-MNT

ATSAMD20G17A-MNT

ATSAMD20G18A-MNT

ATSAMD20G17A-MUTA4

ATSAMD20G14A-MUT

ATSAMD20G15A-MUT

ATSAMD20G16A-MUT

ATSAMD20G17A-MUT

Date: Thursday, July 16, 2020

KSRA-27VTNQ916 - CCB 3658.001 Final Notice: Qualification of MPHL as an additional final test site for selected ATSAMD20G1xx and ATSAMD21G1xx Atmel device families available in 48L VQFN (7x7x0.9 mm) package.

ATSAMD20G18A-MUT

ATSAMD20G17A-MUTA4

ATSAMD20G18A-MUT

ATSAMD20G17A-MUT

ATSAMD20G16A-MUT

ATSAMD20G15A-MUT

ATSAMD20G14A-MUT

ATSAMD20G14A-MUTA2

ATSAMD20G15A-MUTA2

ATSAMD20G16A-MUTA2

ATSAMD20G17A-MUTA2

ATSAMD20G18A-MUTA2

Date: Thursday, July 16, 2020

### KSRA-27VTNQ916

# CCB 3658.001 PRE AND POST CHANGE SUMMARY



A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



Qualification of MPHL as an additional final test site for selected ATSAMD20G1xx and ATSAMD21G1xx Atmel device families available in 48L VQFN (7x7x0.9 mm) package

	Pre Change / ASE9						Post Change /MPHL					
Final Test Location			ASE9			MPHL						
Packing Media		Та	pe and R	eel		Tape and Reel						
Base Quantity Multiple (BQM)		4000	) units pe	r reel		4000 units per reel						
Pin 1 Orientation		(	Quadrant	1		Quadrant 1						
Conviou Tous	Width	Pitch	Ao +/-0.1	Bo +/-0.1	Ko +/-0.1	Width	Pitch	Ao +/-0.1	Bo +/-0.1	Ko +/-0.1		
Carrier Tape	16	12	7.25	7.25	1.10	16	12	7.25	7.25	1.10		



		Pre Cl	nange /	ASE9		Post Change /MPHL					
	Color Diameter Hub Dia W1 +0.3- W2				W2 Max	Color Diameter Hub Dia W1 +0.3- W2					
	White	330	102	8.4	1.1	White	330	102	8.4	1.1	
Reel											
Dessicant	CONTINUE DE LOCATION  CONTINUE DE LOCATION					SOLUPAKIN  PREPRIEDE SECONTS INC  FEED SECONTS INC  FEED SECONTS INC  SOLUPAKIN  PREPRIEDE SECONTS INC  SOLUPAKIN  PREPRIEDE SECONTS INC  SOLUPAKIN  SECONTS INC  SOLUPAKIN  PREPRIEDE SECONTS INC  TELES G-2-22 t-017-0-6  SOLUPAKIN  SECONTS INC  SOLUPAKIN  SECONTS INC					



	Pre Chan	ge / ASE9	Post Change /MPHL				
	Length	Width	Length	Width			
	495	430	457.2	406.4			
Moisture Barrier Bag Dimension (mm)			Mar 15, 2	APERTON  APE			



	Pre	Change / A	SE9	Post Change /MPHL				
	Length 370 mm	Width 353 mm	Height 78 mm	Length 370 mm	Width 353 mm	Height 78 mm		
Carton Box		A		MICROC	DO NOT DROP 禁止摔落 游っあしまり			





#### **QUALIFICATION REPORT SUMMARY**

**PCN #: KSRA-27VTNQ916** 

Date **June 17, 2020** 

Qualification of MPHL as an additional final test site for selected ATSAMD20G1xx and ATSAMD21G1xx Atmel device families available in 48L VQFN (7x7x0.9 mm) package.

Purpose: Qualification of MPHL as an additional final test site for selected

ATSAMD20G1xx and ATSAMD21G1xx Atmel device families available in 48L

VQFN (7x7x0.9 mm) package.

**CCB No.:** 3658.001

Test / Evaluation	Test Conditions / Parameters	RESULT
Datalog / Bin Comparison	<ul> <li>Compare test numbers, test names, test limit, test sequence, bin assignments &amp; pass/fail results.</li> <li>Accept if all match or justify the differences results.</li> </ul>	PASSED
Site by site verification	Verifies the channel map has the correct site assignments and tester/handler communication work correctly	PASSED
Correlation lot report	<ul> <li>Yield at each step and reject analysis between systems.</li> <li>5K units are tested for each program conversion we perform.</li> </ul>	PASSED
Unit to unit parametric correlation	A full assembly strip characterized on both systems and graphed vs each other & the data sheet limits	PASSED
Test stability	<ul> <li>50 loop test performed with no datalog delays</li> <li>Accept on 0 fails</li> </ul>	PASSED
Parametric test stability verification	<ul> <li>Use Real Time Statistics software to create CPK report of all parametric tests</li> <li>Accept on Cpk &gt; 1.67 or explainable</li> </ul>	PASSED